

SCANNING MICROSCOPY 2009 PROGRAM SCHEDULE

Monday			
Morning	Course: Software for Scanning Microscopy		
Afternoon	Course: Basics and Industrial Applications of AFM		
Tuesday			
	Room 1 (7378A)	Room 2 (7378B)	Room 3 (7378C)
Morning Session 1	Introduction and Plenary Session		
Morning Session 2	Helium Ion Microscopy	Atomic Force and Scanned Probe Microscopies I	Microscopy and Analysis of Biological Materials I
Afternoon Session 1	Helium Ion Microscopy: Even More Gas	Atomic Force and Scanned Probe Microscopies II	Microscopy and Analysis of Biological Materials II
Afternoon Session 2	Sample Preparation Technology	Microscopy and Analysis of Food Microstructures	Microscopy Applications in Environmental Safety and Health
Wednesday			
Morning Session 1	Focused Ion Beam Microscopy I	Course: SC954: Scanning Microscopy in Forensic Science	Optical Microscopies I
Morning Session 2	Focused Ion Beam Microscopy II		Optical Microscopies II
Afternoon Session 1	Microspectroscopic Characterization with Multiple Probes I		Optical Characterization of Biological Materials
Afternoon Session 2	Microspectroscopic Characterization with Multiple Probes II		
Thursday			
Morning Session 1	Scanning Electron Microscopies I	Late Breaking Papers (To be announced)	Applications of Scanning Microscopy to Forensics Science I
Morning Session 2	Scanning Electron Microscopies II		Applications of Scanning Microscopy to Forensics Science II
Afternoon Session 1	Scanning Electron Microscopies III		Applications of Scanning Microscopy to Forensics Science III
Afternoon Session 2	Electron Beam Interaction Modeling Workshop Session		Forensics Forum
	Discussion of NIST DTSA-II for Spectral Modeling		